SPECNo: GS-BF-EN-041

**REV:2** 

FOR T-Flash Card SERIES CONNECTOR

Page 1 of 5

#### 1.0 SCOPE

This Product Specification covers the T-Flash Card Series connector.

#### 2.0 APPLICABLE DOCUMENTS AND SPECIFICATIONS

See sales drawings and other sections of this specification for the relevant reference documents. In cases where the specification differs from the drawings, the drawings take precedence.

#### **3.0 DESIGN AND CONSTRUCTION**

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

#### **4.0 MATERIALS**

See attached drawings

#### **5.0 RATINGS**

Rated current) : 0.5A max Rated voltage): 30 V max

Operating Temperature) :-40 °C to +85°C

Storage Temperature): -5°C to +80°C

APPROVED BY: <u>Haiyong</u> CHECKED BY: <u>Max</u> VERIFIED: <u>Teddy</u>

SPECNo: GS-BF-EN-041

**REV:2** 

FOR T-Flash Card SERIES CONNECTOR

Page 2 of 5

# 6. ELECTRICAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITIN	REQUIREMENT			
6.1	Contact Resistance	Mate connectors with dry circuit(20mV,10mA Max) Spec: EIA-364-23B	Less than $100m\Omega$			
6.2	Insulation Resistance	When applied DC 100V between adjacent terminal or ground 500V DC Spec: EIA-364-21C	More than 1000MΩ			
6.3	Dielectric strength	No change				

# 7.MECHANICAL REQUIREMENT

ITEM	DESCRIPTION	TEST CONDITIN	REQUIREMENT		
7.1	Durability	Operation Speed: 400~600 cycles/H. Durability Cycles: 3000 Cycle	No mechanical damage Contact Resistance: 100mΩMax		
7.2	Mating and Unmating force	Measures force necessary to mate connector assemblies at a rate of 25±3mm/Min Spec: EIA-364-13B	Mating force 10N Max Unmating force 0.5N Min 10N Max		

SPECNo: GS-BF-EN-041

**REV:2** 

FOR T-Flash Card SERIES CONNECTOR

Page 3 of 5

ITEM	DESCRIPTION	TEST CONDITIN	REQUIREMENT		
8.1	Cold Resistance	Solder connectors on PCB ,expose to -40±3°C for 48 hours. Upon completion of the exposure period, the test specimens shall be conditioned at ambient room conditions for 1 of 2 hours, after which the specified measurements shall be performed.	No mechanical damage Contact Resistance:100mΩ Max		
8.2	Thermal Shock	Samples shall be placed in the test chamber with the test condition for 5 cycles:Temperature(°C)-55+25+85+25Time(minute)305305Spec:EIA 364-32A	No mechanical damage Contact Resistance: 100mΩMax Insulation Resistance: 500MΩMin		
8.3	Humidity Life	The connectors shall be mated and exposed to the condition of $40 \pm 2$ °C with 90~95% Humidity for 96 hour; Recovery time 1~2 hours Spec: EIA-364-31B	No mechanical damage Contact Resistance: 100mΩMax Insulation Resistance: 500MΩMin		
8.4	Temperature Life(Heat Aging)	Mated Connector $85^{\circ}$ C, 96 hours Upon completion of the exposure period, the test specimens shall be conditioned at ambient room conditions for 1 of 2 hours,	No mechanical damage Contact Resistance: 100mΩMax		

SPECNo: GS-BF-EN-041

FOR T-Flash Card SERIES CONNECTOR

NECTOR REV:2

Page 4 of 5

ITEM	DESCRIPTION	TEST CONDITIN	REQUIREMENT		
8.5	Solder ability	The surfaces to be tested shall be immersed in flux for a minimum of $5\pm0.5$ seconds. the temperature of the solder bath shall be maintained as measured below the surface on the solder at $235^{\circ}C\pm2^{\circ}C$ Spec: EIA 364-52	No mechanical damage coverage: 95%Mir		
8.6	Salt Spray	Subject mated connectors to 35+/-2 °C and 5+/-1% salt condition for 48hours. After test, rinse the sample with water and recondition the room temperature for 2 hour	No detrimental corrosion allowed in contact area. contact resistance ≦100 mΩ		
8.7	Resistance to soldering heat	$\frac{2-4C^{\circ}/\sec}{120\sec \text{ Min}}$ $\frac{2-4C^{\circ}/\sec}{120\sec \text{ Min}}$ $\frac{220^{\circ}\text{C}}{(120\sec \text{ Min})}$ $\frac{220^{\circ}\text{C}}{(60\sec \text{ Min})}$ $\frac{2-4C^{\circ}/\sec}{11\text{ ME}}$ test condition for reflow soldering Spec: MIL-STD-202 F, Method 210 A	No evidence of physical damage		

ENGINEERING DEPT

# **PRODUCT SPECIFICATION**

SPECNo: GS-BF-EN-041

### FOR T-Flash Card SERIES CONNECTOR

REV:2

Page 5 of 5

		Test Group									
Test Item		А	В	С	D	E	F	G	н	I	J
		Test Sequence									
1	Examination of Product	1,5	1,3	1,5	1,5	1,7	1,7	1,5	1,5	1,3	1,3
2	Contact Resistance	2		2,4	2,4	2,6	2,6	2,4	2,4		
3	Insulation Resistance	3				3,5	3,5				
4	Withstanding Voltage Test	4									
	Mating and Unmating Force		2								
5	Durability			3							
6	Cold Resistance				3						
7	Thermal Shock					4					
8	Humidity Life						4				
9	Temperature Life(Heat Aging)							3			
10	Salt Spray								3		
11	Solder ability									2	
12	Resistance to soldering heat										2
13	No. of Test Samples (Min.)	5	5	5	5	5	5	5	5	5	5